


<b>Search Notes</b> 	<b>Application/Control No.</b> 10736690	<b>Applicant(s)/Patent Under Reexamination</b> ARELLANO ET AL.
	<b>Examiner</b> Parker, Brandon	<b>Art Unit</b> 2174

SEARCHED			
Class	Subclass	Date	Examiner
715	863	2/1/07	BP
715	530	2/1/07	BP
715	764	2/1/07	BP
715	762	2/2/07	BP

SEARCH NOTES			
Search Notes		Date	Examiner
SEARCHED IEEE AND ACM		2/1/07	BP

INTERFERENCE SEARCH			
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